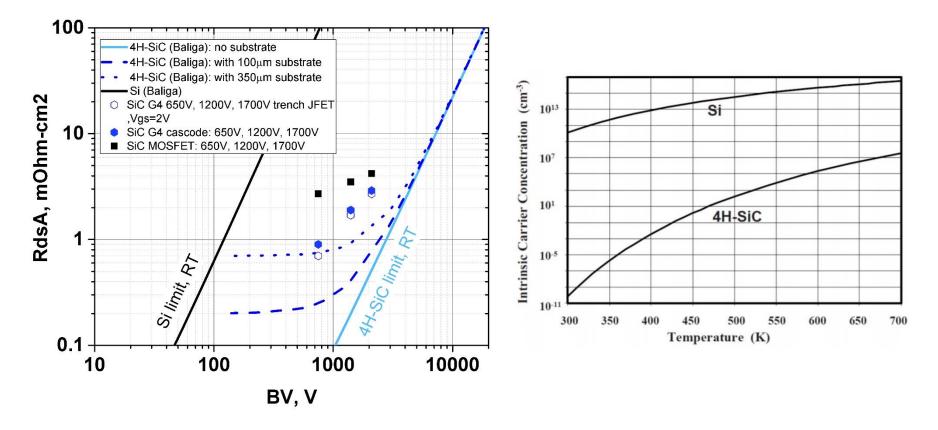
FREESTA SYSTEMS CENTER

SiC JFETs for Circuit Protection



Why SiC?



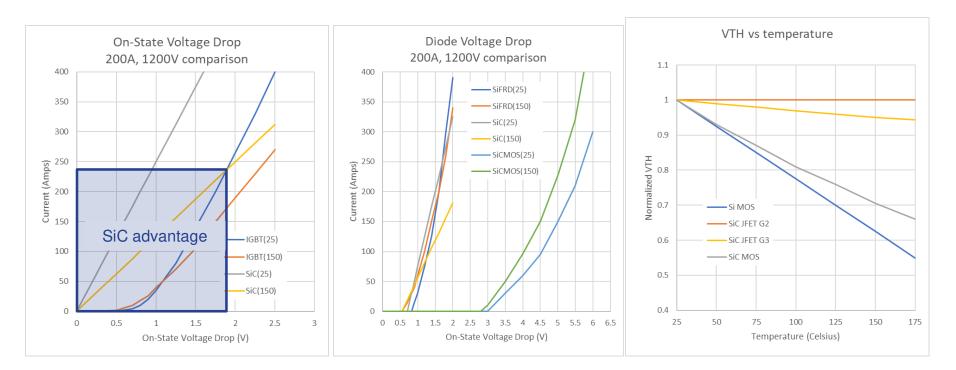


Key properties

- Low RdsA for a given BV for unipolar devices, due to 10X higher E_{CRIT}
- High peak operating temperatures
- 3X Higher thermal conductivity than Si
- Ability to handle 4X energy to failure than Si per unit area

SiC FET Advantages ≥ 1200V





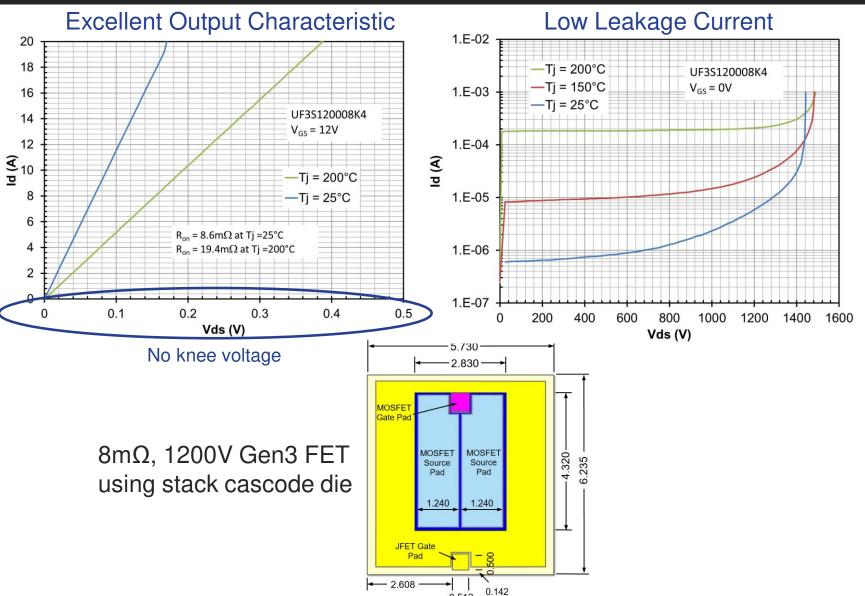
Normally-on SiC JFETs offer lowest RdsA

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- IGBTs great at high currents, but knee voltage leads to unwanted losses in most operating conditions
- Normally-off FET created using stack cascode, Si MOSFET on SiC JFET
 - Si MOSFET adds Rds, but operates at a positive Vgs
 - Excellent reverse conduction characteristic, similar to Si diode
 - No gate oxide degradation issues
- Normally-on JFET Vth is insensitive to temperature more thermally stable

1200V SiC Stack Cascode Example





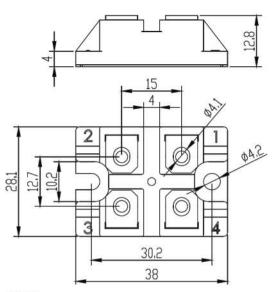
0.512

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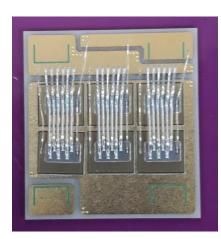
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$2m\Omega$, 1200V SOT-227 SiC FET





Unit: mm



United SiC

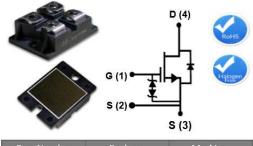
xJ SiC Series | $1.8m\Omega$ - 1200V SiC Cascode | UF3SC120002SNS

Datasheet

Description

Features

United Silicon Carbide's cascode products co-package its highperformance F3 SiC fast JFETs with a cascode optimized MOSFET to produce the only standard gate drive SiC device in the market today. This device is ideally suited for circuit breaker, solid state switch and synchronous rectification applications, using a standard gate drive, and providing very high current capability in the familiar SOT227 footprint. The baseplateless construction with advanced internal packaging provides very low thermal impedence.



Part Number	Package	Marking		
UF3SC120002SNS	SOT-227	UF3SC120002SNS		

Typical Applications

- EV charging
- Synchronous rectifiers
- Solid state circuit breakers
- Solid state load switch
- Motor drives
- Induction heating

AIN for improved RthJC

SOT227 package for high current handling

Typical on-resistance $R_{DS(on,typ}$ of $1.8m\Omega$

Maximum operating temperature of 175°C

Standard 12V gate drive

Excellent Reverse Recovery

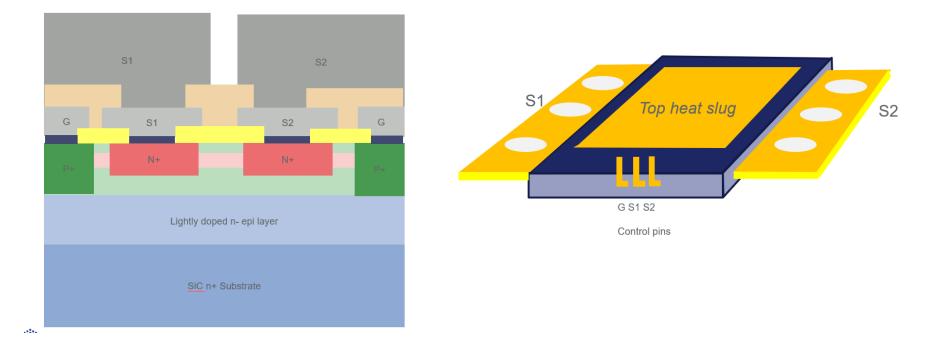
Low intrinsic capacitance

ESD protected, HBM class 2

Low gate charge

- Ag sinter interfaces
- Au plated bottom
- Package can be sintered to heat sink





- For very low voltages and bidirectional circuit breakers, this lateral structure eliminates substrate resistance
- With state-of-the-art packaging, 1mΩ, 100V 3x6mm² chips can be paralleled to form high current breakers with resistances < 0.1mΩ



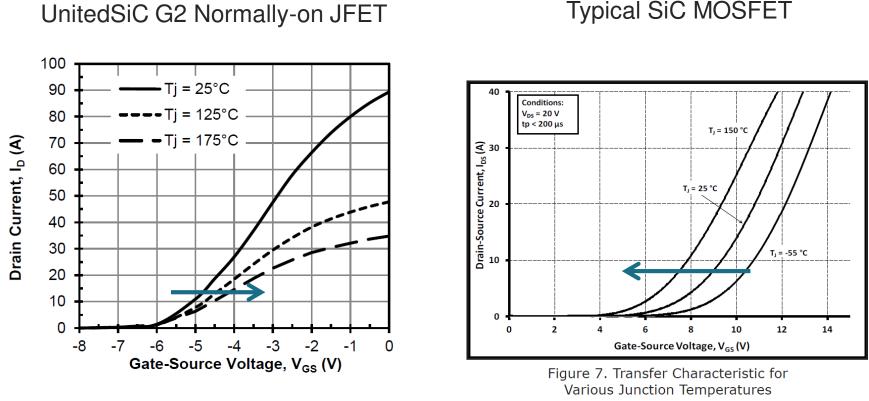


Figure 6 Typical transfer characteristics at V_{DS} = 5V

Unlike SiC or Si MOSFETs, JFETs can be held stably in active mode, since the V_{GS} needed to sustain a given current increases with temperature, even down to relatively low currents

MOSFET Hot Spot in Active Mode



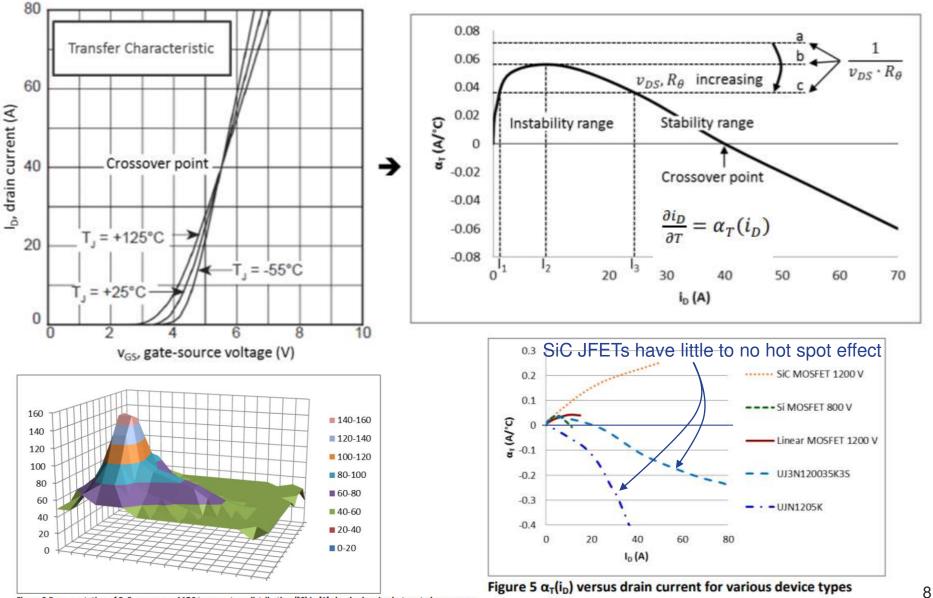
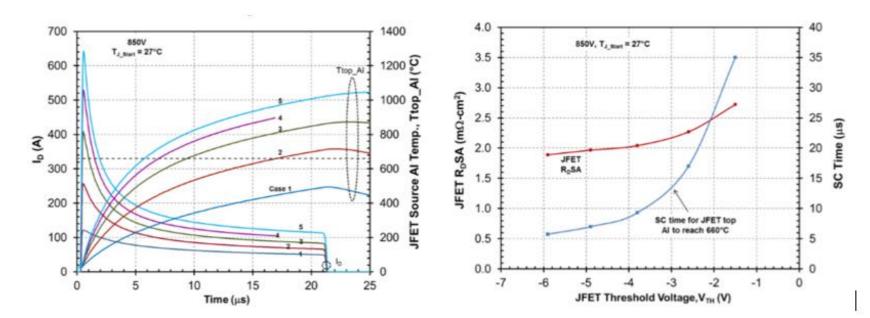


Figure 2 Representation of 5x5 mm power MOS temperature distribution (°C) in [1] clearly showing hot spot phenomenon

SiC JFET/Cascode Short Circuit





• RdsA tradeoff for trench SiC JFETs (UJC1206K)

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• Peak saturation current can be decreased with little Rdson penalty

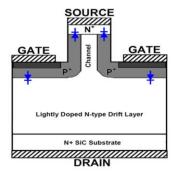
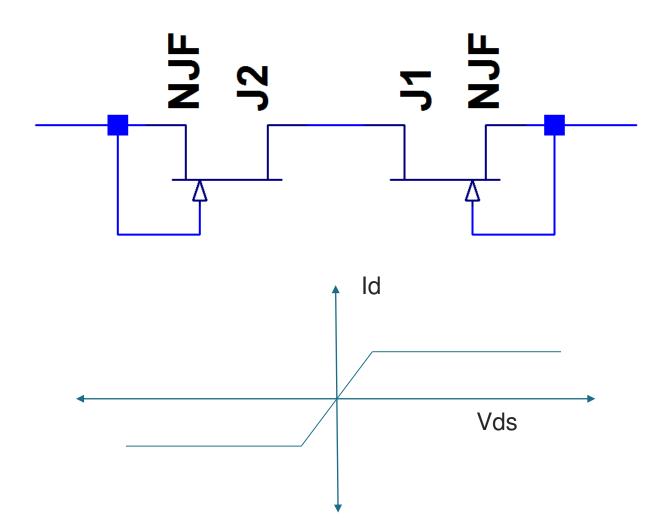


Figure 1: Cell structure of <u>SiC</u> trench JFET.



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FREE Setup for Electrothermal Simulations



Surge waveform WF5A Vpeak (open circuit voltage) = 1500VSource impedance = 1Ω

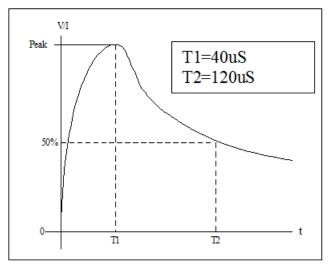


Figure 2 Example Surge Waveform (WF5A)

Layer (From top to bottom)	Thickness um	Thermal Conductivity W/(K cm)	Heat Capacity J/(K cm ³)		
SiO2 (Pkg mold)	200	0.014	1.67		
Aluminum	5	2.38	2.33		
SiC	371.5	4.55	1.63		
Solder	25	0.36	1.57		
Copper (baseplate)	200	3.85	3.42		

SiO2 200um to model compound thermal insulating region

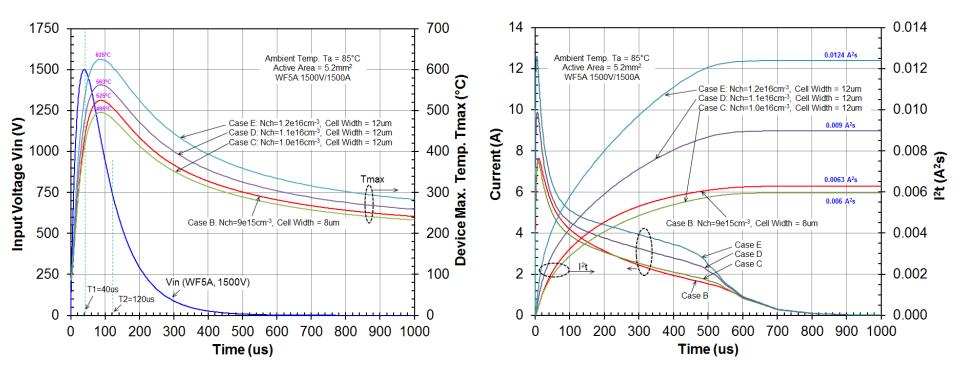
Top Al 5um
SiC Surface region – detail not shown
SiC 371.5um
Solder 25um
Cu 200um

UnitedSiC confidential



Transient Thermal Simulations WF5A 1500V/1500A



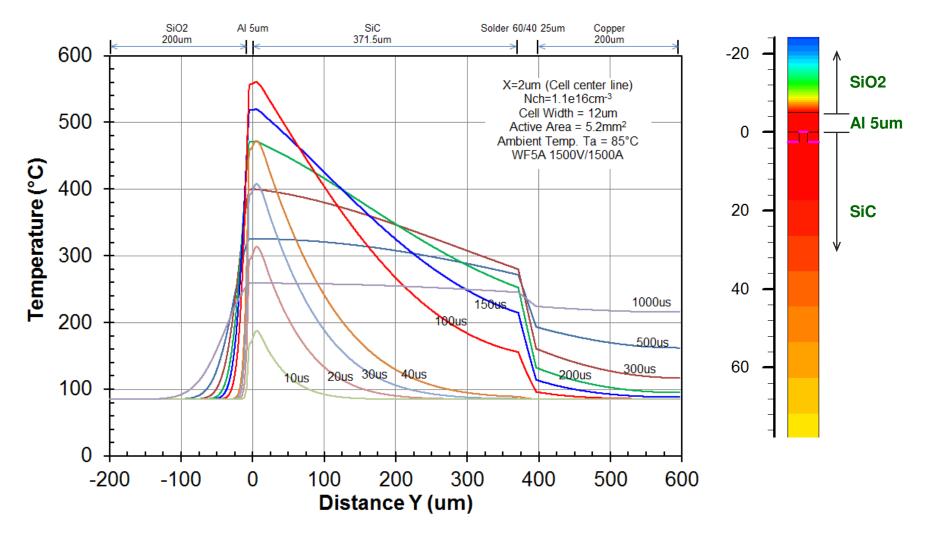


	Design	Ron (Ω)	lsat @8 @10V	35°C (A) @1.5kV	Tmax (°C)	lmax (A)	l²t (A²s)	
Recommended Design	Case B	0.58	2.5	12.3	525	7.6	0.0063	8um pitch
Design	Case C	0.56	3.2	11.5	495	7.5	0.0060	
	Case D	0.45	5.2	15.6	563	9.8	0.0090	12um pitch
	Case E	0.39	7.4	19.9	625	12.6	0.0124	



Temperature Distribution along Device Vertical Center Line for Design Case D

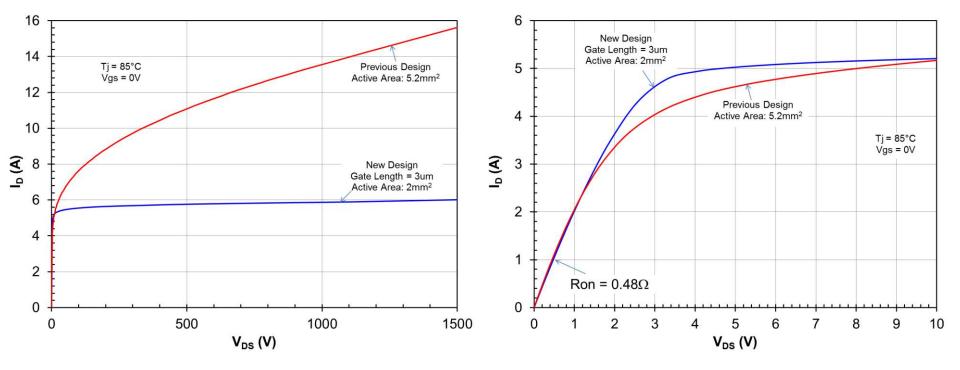




Improved Current limiter DC Characteristics at 85°C SYSTEMS CENTER

F

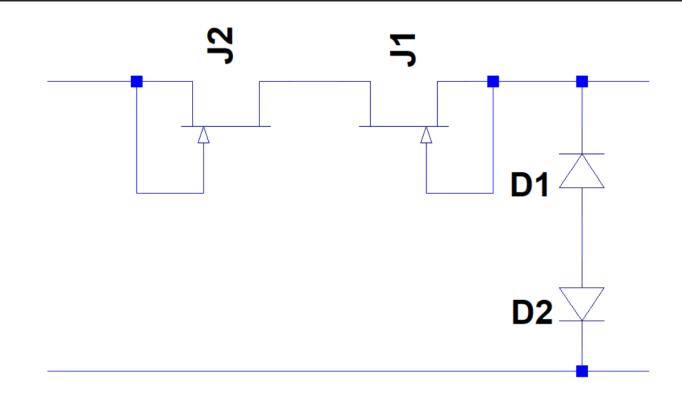




Avoid DIBL type effects for better saturation

Inrush and Overvoltage Protection





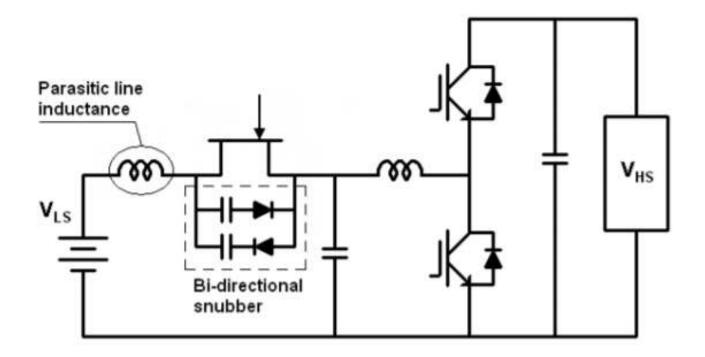
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Common-drain JFETs – bidirectional inrush current limiting

D1,D2 – TVS diodes. Use Si at low voltages, SiC at high voltage







A MOV may be used across the SD if the line inductance energy becomes too high.



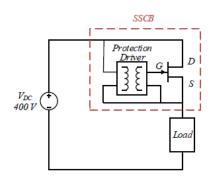


Fig. 1. A unidirectional self-powered SSCB using a normally-on SiC JFET as the main static switch and a fast-starting isolated DC/DC converter as the protection driver.

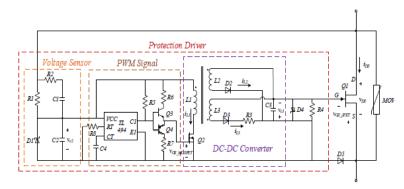


Fig. 2. A detailed circuit schematic of the SSCB with a combined forward-flyback DC/DC converter design.

Courtesy of the Illinois Institute of Technology

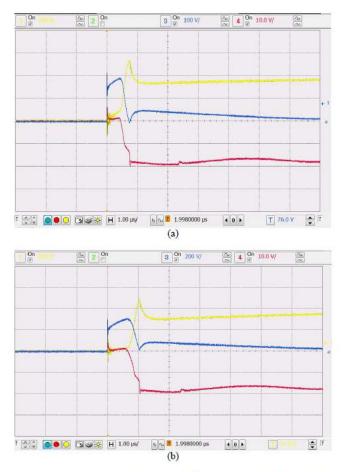


Fig. 9. Short circuit switching waveforms of SSCB with a combined forward-flyback protection driver with (a) 1 Ω , and (b) 2 Ω short circuit loop resistance. Time scale: 1 µs/division. BLUE is the JFET drain current i_{DS} waveform (100A/division). YELLOW is the JFET drain-source voltage v_{DS} waveform (200V/division). RED is the SiC JFET gate voltage $v_{GS,JFET}$ waveform (10V/division). The response time is about 0.8 µs and 1 µs for (a) and (b) respectively.

Multi-Stage JFET Based Breaker



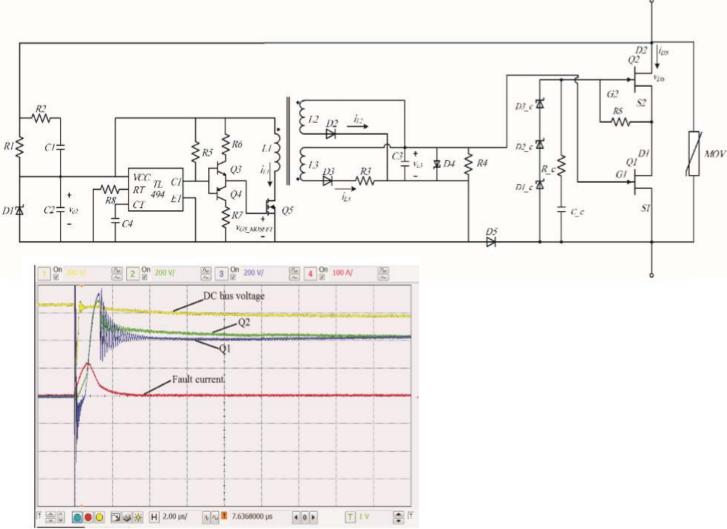


Fig. 7. Measured V_{DS} switching waveforms of Q1 (blue) and Q2 (green) during a short circuit fault. Time scale: 2 μ s/division.

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Courtesy of the Illinois Institute of Technology

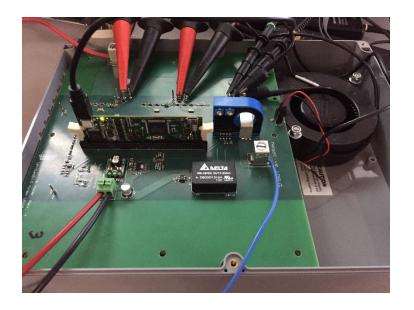
Controlled Current DC SSCB

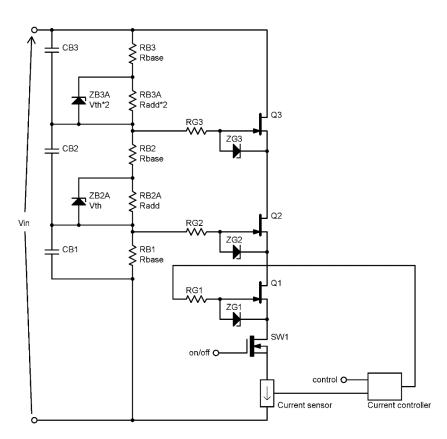


- Voltages automatically balanced
- Current controlled at any operating voltage
 - Soft start

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- Capacitor precharge
- Fault ride-through current limiter
- High voltage capability with fast turn-off feature





- Even if not operating at high voltage...
 - Multiple JFETs dissipating power
 - One current controller
 - Lower cost than paralleling

Controlled Current AC SSCB

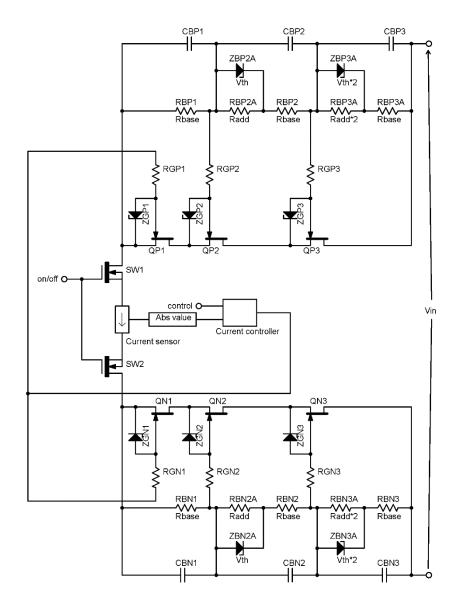


 AC current controlled with alternating voltage applied

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- Clean AC motor start
- Fault ride-through current limiter
- Bidirectional blocking, fast turnoff feature
- JFETs in reverse conduction are biased fully on because JFET is on when $v_{GS} - v_{DS} > V_{GS(th)}$. When v_{DS} is negative, JFET turns on more with increasing magnitude of its v_{DS} (caused for example by increased current through it), thus creating a positive reinforcement of turning on.

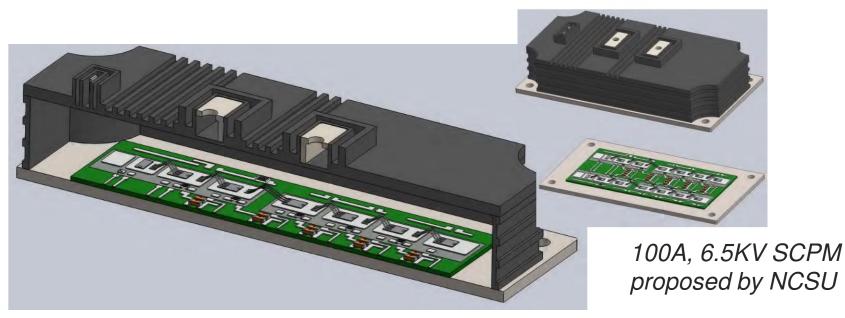


FREEDM HV Supercascodes



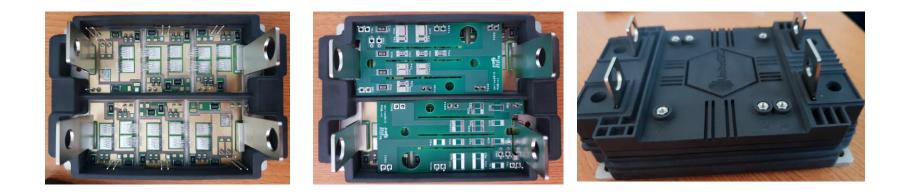


15KV, 40A built with discrete 45m, 1200v JFETs NCSU

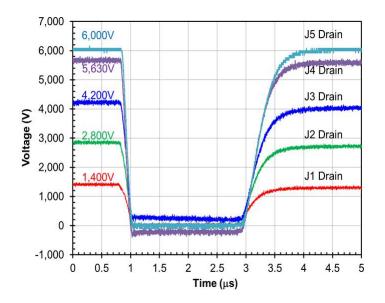


FREE High Voltage Applications





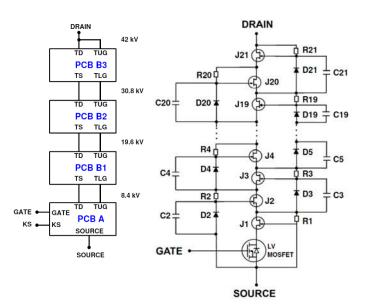
- 200A, 6500V half-bridge
- Solid state transformers, MV-XFC fast chargers, wind, traction, HVDC
- Uses a 5.7m, 1700V SiC JFET
- Can be utilized for HV DC breakers



Ultra High Voltage Switches







1A, 40KV Demo

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1.E-03

1.E-04

1.E-05

1.E-06

0

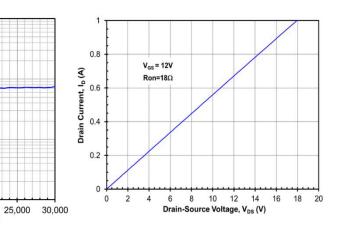
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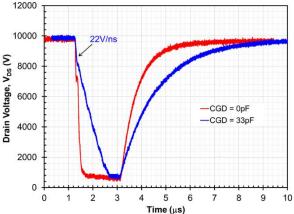
10,000

15,000 20,000

Drain-Source Voltage, V_{DS} (V)

Drain Current, I_D (A)







Questions



Anup Bhalla V.P. Engineering abhalla@unitedsic.com



Property	Si	GaAs	6H-SiC	4H-SiC	GaN	Diamond
Bandgap, Eg (eV)	1.12	1.43	3.03	3.26	3.45	5.45
Dielectric constant, ε_r^{I}	11.9	13.1	9.66	10.1	9	5.5
Electric Breakdown Field, E _c (kV/cm)	300	400	2500	2200	2000	10000
Electron Mobility, μ_n (cm ² /V·s)	1500	8500	500 80	1000	1250	2200
Hole Mobility, $\mu_p (\mathrm{cm}^2/\mathrm{V}\cdot\mathrm{s})$	600	400	101	115	850	850
Thermal Conductivity, λ (W/cm·K)	1.5	0.46	4.9	4.9	1.3	22
Saturated Electron Drift Velocity, v_{sat} (×10 ⁷ cm/s)	1	1	2	2	2.2	2.7

Table I: Physical characteristics of Si and main wide bandgap semiconductors [1-3].

¹ $\varepsilon = \varepsilon_r \cdot \varepsilon_o$ where $\varepsilon_o = 8.85 \times 10^{-12} \text{ F/m}$